

REVIEW FOR EXAMINATION NO.1

Examination No. 1 will be given during class on Monday, February 9, 2004 from 12:05pm to 12:55pm. It will last for 50 minutes and is open book. The exam will consist of approximately 4 problems. Below is a list of the material for which you are responsible.

Deep Submicron Digital IC Design

Review of Digital Logic Gate Design

Basic logic functions

- DeMorgan's Laws
- Sequential Logic Circuits

Implementation of Logic Circuits

- Characteristics

Noise Margins

Propagation Delay Time

Power

- Static
- Dynamic

MOS Transistors

Structure and operation of MOSFETs

- Equivalent ON and OFF resistances

Threshold voltage of the MOSFET

- Equation (2.11) – its components and their meaning and the parameters of Eq. (2.11)

Development and application of the First-Order (Sah model) Current-Voltage

Characteristics

Development and application of the Velocity-Saturated Current-Voltage Model

Application and understanding of the Subthreshold Conduction Model

Capacitances of the MOSFET

- Thin-oxide (intrinsic capacitances)
- PN-junction capacitances (depletion capacitances)
- Overlap capacitances (intrinsic capacitances)

The summary in Sec. 2.9 is key to this section – you must know these formulas, what they mean and how to apply them.

Fabrication, Layout and Simulation

IC Fabrication Technology

- What are the five major processing steps in IC technology? Also you should know about the epitaxial process
- Photolithography process – what is it and how is it applied
- Know the physical aspects of the MOSFET – cross-section
- Connections – metal, vias, etc.

Calculation of capacitance and resistance of a conductor

Calculating the resistance and capacitance associated with the physical layout of a MOSFET

Circuit simulation models for the MOSFET

SPICE – Level 1 model and parameters

Extraction of the level 1 model parameters

Temperature dependence of MOSFETs for the various regions of operation

Voltage limitations

Latchup